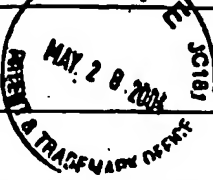
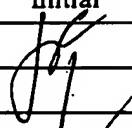
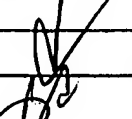


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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT			Applicant: Ulrich Bonne et al.	
			Filing Date:	Group Art:
			September 26, 2003	unknown 2856


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EXAMINER: 	DATE CONSIDERED: 8/26/04

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	Filing Date: September 26, 2003	Group Art: unknown 2856

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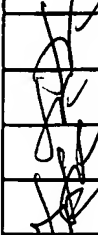
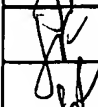
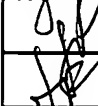

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

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Examiner Initial	Document No.	Date	Country	Translation Yes No
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